

September 1990  
Edition 1.0

DATA SHEET

FUJITSU

## MB8299-25/-35

# CMOS 288K-BIT HIGH-SPEED BiCMOS SRAM

### 32K Words x 9 Bits BiCMOS High-Speed Static Random Access Memory

The Fujitsu MB8299 is a high-speed static random access memory organized as 32,768 words x 9 bits and fabricated with CMOS technology. To obtain a smaller chip size, the cells use NMOS transistors and resistors. The MB8299 is housed in 300 mil plastic DIP and SOJ packages, and a 450 mil SOP package. All pins are TTL compatible and a single +5 V power supply is required.

A separate chip select (CS<sub>1</sub>) pin simplifies multipackage systems design by permitting the selection of an individual package when outputs are OR-tied, and then automatically powering down the other deselected packages.

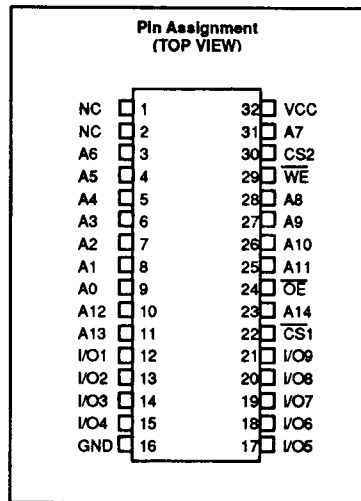
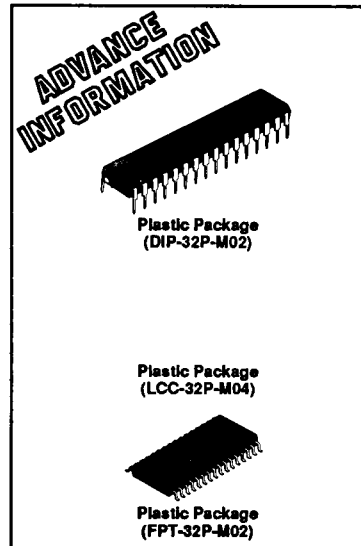
The MB8299 offers low power dissipation, low cost, and high performance.

- Organization: 32,768 words x 9 bits
- Static operation: no clocks or timing strobe required
- Access time:  $t_{AA} = t_{ACS} = 25$  ns max. (MB8299-25)  
 $t_{AA} = t_{ACS} = 35$  ns max. (MB8299-35)
- Low power consumption: 715 mW max. (Operating) for 25 ns  
605 mW max. (Operating) for 35 ns  
138 mW max. (TTL Standby)  
27.5 mW max. (CMOS Standby)
- Single +5 V power supply  $\pm 10\%$  tolerance
- TTL compatible inputs and outputs
- Three-state outputs with OR-tie capability
- Electrostatic protection for all inputs and outputs
- Standard 32-pin Plastic Packages:
  - Skinny DIP (300 mil) MB8299-xxPSK
  - SOJ (300 mil) MB8299-xxPJ
  - SOP (450 mil) MB8299-xxPF

### Absolute Maximum Ratings (See Note)

| Rating  | Symbol     | Value       | Unit        |
|---|------------|-------------|-------------|
| Supply Voltage                                    | $V_{CC}$   | -0.5 to +7  | V           |
| Input Voltage on any pin with respect to GND      | $V_{IN}$   | -3.5 to +7  | V           |
| Output Voltage on any I/O pin with respect to GND | $V_{OUT}$  | -0.5 to +7  | V           |
| Output Current                                    | $I_{OUT}$  | $\pm 20$    | mA          |
| Power Dissipation                                 | $P_D$      | 1.0         | W           |
| Temperature Under Bias                            | $T_{BIAS}$ | -10 to +85  | $^{\circ}C$ |
| Storage Temperature Range                         | $T_{STG}$  | -45 to +125 | $^{\circ}C$ |

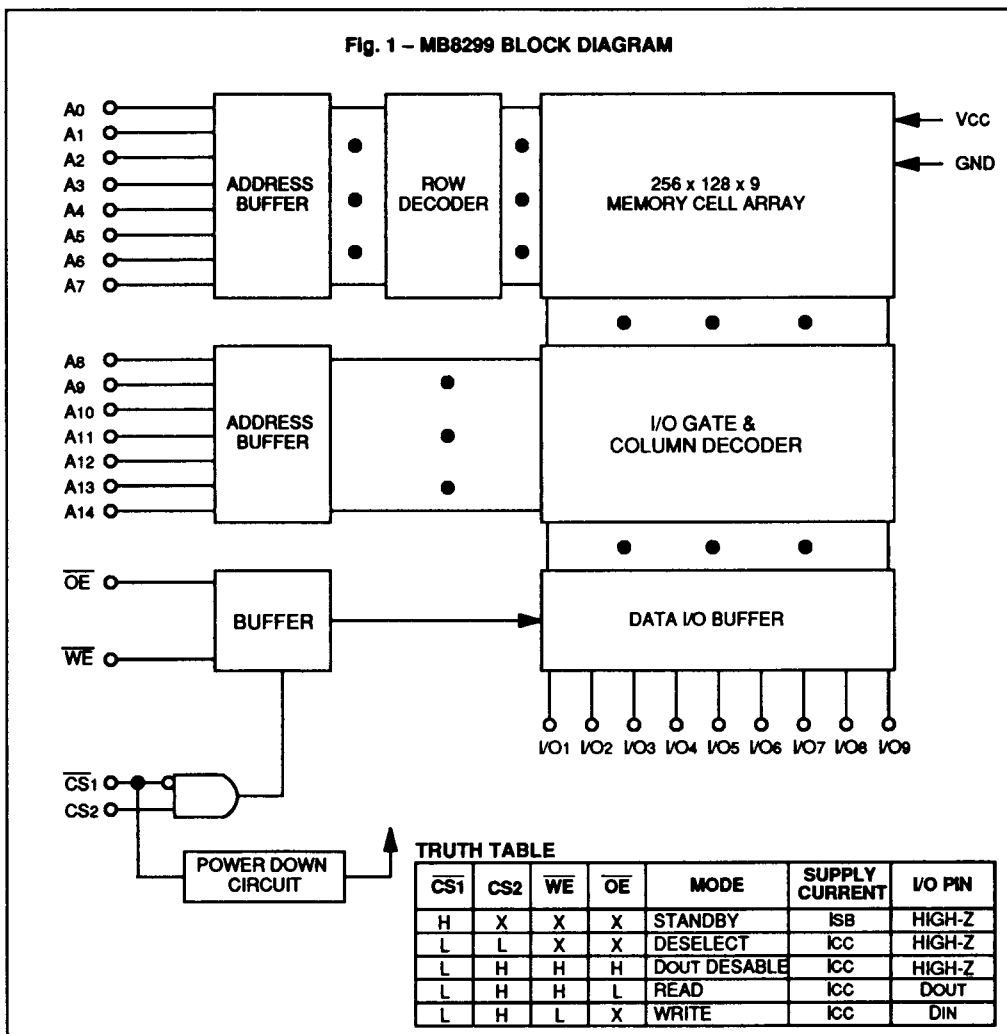
**Note:** Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltage to this high impedance circuit.

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**MB8299-35**

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**CAPACITANCE** ( $T_A = 25^\circ\text{C}$ ,  $f = 1\text{MHz}$ )

| Parameter  | Condition      | Symbol | Min | Typ | Max | Unit |
|--|----------------|--------|-----|-----|-----|------|
| Input Capacitance ( $\overline{\text{CS1}}$ , $\text{CS2}$ , $\overline{\text{OE}}$ , $\overline{\text{WE}}$ ) | $V_{IN} = 0V$  | C11    |     |     | 8   | pF   |
| Input Capacitance (Other Input)  | $V_{IN} = 0V$  | C12    |     |     | 7   | pF   |
| I/O Capacitance  | $V_{I/O} = 0V$ | C1/O   |     |     | 8   | pF   |

**RECOMMENDED OPERATING CONDITIONS**

(Referenced to GND)

| Parameter           | Symbol | Min | Typ | Max | Unit |
|---------------------|--------|-----|-----|-----|------|
| Supply Voltage      | VCC    | 4.5 | 5.0 | 5.5 | V    |
| Ambient Temperature | TA     | 0   |     | 70  | °C   |

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**DC CHARACTERISTICS**

(Recommended operating conditions unless otherwise noted.)

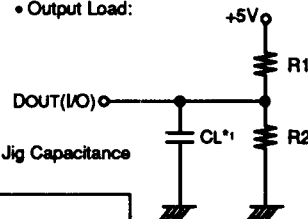
| Parameter                | Symbol | Test Condition   | Min    | Max | Unit    |
|--------------------------|--------|--|--------|-----|---------|
| Standby Supply Current   | ISB1   | $\overline{CS1} \geq VCC - 0.2V$<br>$VIN \geq VCC - 0.2V$ or $VIN \leq 0.2V$                           |        | 5   | mA      |
|                          | ISB2   | $VIN \leq 0.2V$<br>$\overline{CS1} = VIH$  |        | 25  | mA      |
| Operating Supply Current | ICC    | $I_{OUT} = 0mA$ , $\overline{CS1} = VIL$<br>Cycle = Min.   |        | 130 | mA      |
|                          |        |  |        | 110 |         |
| Input Leakage Current    | ILI    | $VIN = 0V$ to VCC, VCC = Max.  | -5     | 5   | $\mu A$ |
| Output Leakage Current   | ILIO   | $\overline{CS1} = VIH$ or $CS2 = VIL$ or<br>$\overline{WE} = VIL$ or $OE = VIH$ ,<br>$VIO = 0V$ to VCC | -5     | 5   | $\mu A$ |
| Input Low Voltage        | VIL    |  | -2.0*1 | 0.8 | V       |
| Input High Voltage       | VIH    |  | 2.2    | 6.0 | V       |
| Output High Voltage      | VOH    | $I_{OH} = -4mA$  | 2.4    |     | V       |
| Output Low Voltage       | VOL    | $I_{OL} = 8mA$   |        | 0.4 | V       |

Note: \*1 -2.0V Min. for pulse width less than 20% of cycle time. (VIL min.—0.5V at DC level)

Fig. 2 - AC TEST CONDITIONS

- Input Pulse Levels: 0V to 3.0V
- Input Pulse Rise & Fall Times: 3ns (Transient between 0.8V and 2.2V)
- Timing Reference Levels: Input :  $VIL=0.8V$ ,  $VIH=2.2V$   
Output :  $VOL=0.8V$ ,  $VOH=2.2V$

• Output Load:



\*1 Including Scope and Jig Capacitance

|         | R1            | R2           | CL   | Parameters Measured                                    |
|---------|---------------|--------------|------|--|
| Load I  | 480k $\Omega$ | 255 $\Omega$ | 30pF | except tLZ1, tLZ2, tHZ1, tHZ2, tWZ, tOW, tOLZ and tOHZ |
| Load II | 480k $\Omega$ | 255 $\Omega$ | 5pF  | tLZ1, tLZ2, tHZ1, tHZ2, tWZ, tOW, tOLZ and tOHZ        |

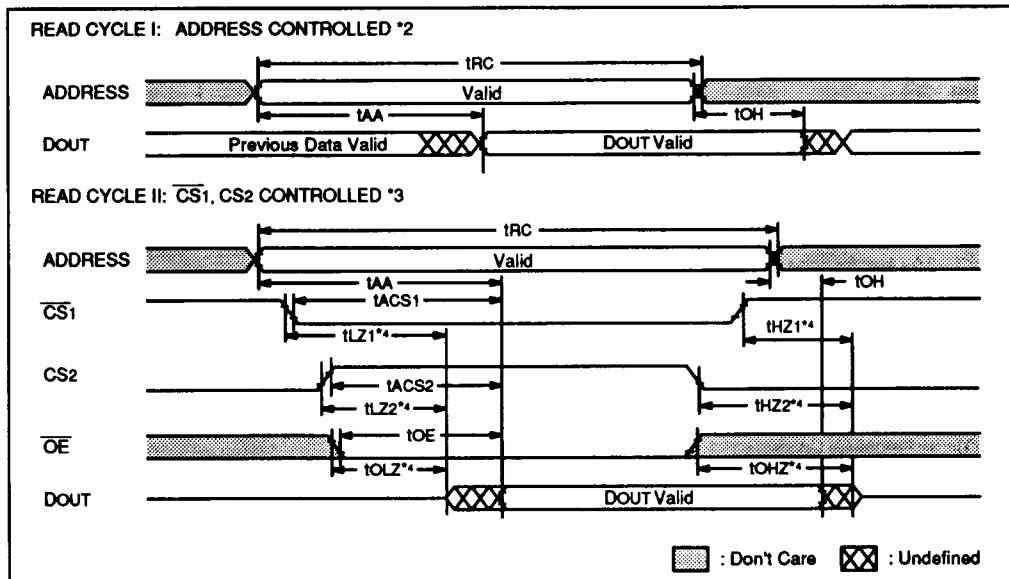
**MB8299-25**  
**MB8299-35**

## AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

| Parameter                              | Symbol            | MB8299-25 |     | MB8299-35 |     | Unit |
|--|-------------------|-----------|-----|-----------|-----|------|
|  |                   | Min       | Max | Min       | Max |      |
| Read Cycle Time                        | t <sub>RC</sub>   | 25        |     | 35        |     | ns   |
| Address Access Time *2                 | t <sub>AA</sub>   |           | 25  |           | 35  | ns   |
| CS1 Access Time *3                     | t <sub>ACS1</sub> |           | 25  |           | 35  | ns   |
| CS2 Access Time *3                     | t <sub>ACS2</sub> |           | 14  |           | 15  | ns   |
| OE Access Time                         | t <sub>OE</sub>   |           | 12  |           | 14  | ns   |
| Output Hold from Address Change        | t <sub>OH</sub>   | 3         |     | 3         |     | ns   |
| Output Low-Z from $\overline{CS1}$ *4  | t <sub>lZ1</sub>  | 5         |     | 8         |     | ns   |
| Output Low-Z from CS2 *4               | t <sub>lZ2</sub>  | 2         |     | 3         |     | ns   |
| Output Low-Z from $\overline{OE}$ *4   | t <sub>OLZ</sub>  | 2         |     | 3         |     | ns   |
| Output High-Z from $\overline{CS1}$ *4 | t <sub>hZ1</sub>  | 1         | 15  | 1         | 15  | ns   |
| Output High-Z from CS2 *4              | t <sub>hZ2</sub>  | 1         | 15  | 1         | 15  | ns   |
| Output High-Z from $\overline{OE}$ *4  | t <sub>OHZ</sub>  | 1         | 15  | 1         | 15  | ns   |

### READ CYCLE TIMING DIAGRAM \*1

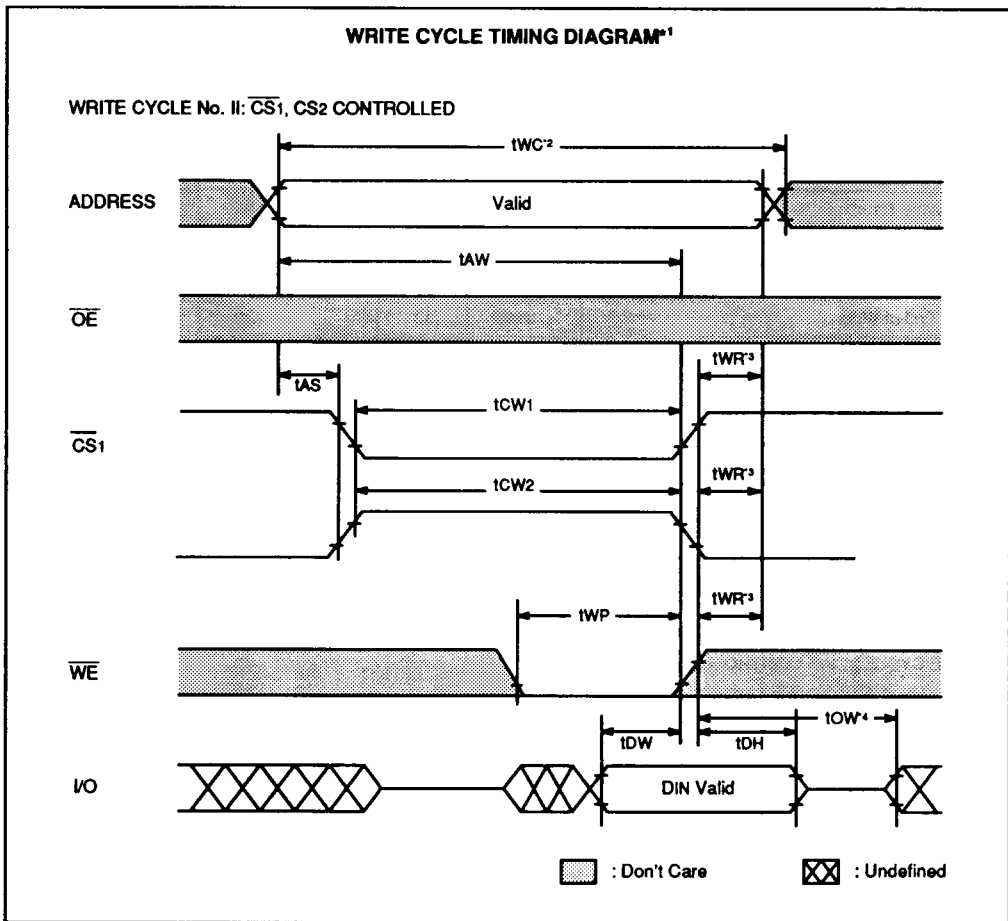


- Note:**
- \*1  $\overline{WE}$  is high for Read Cycle.
  - \*2 Device is continuously selected,  $\overline{CS1} = \text{VIL}$ ,  $\text{CS2} = \text{VIH}$  and  $\overline{OE} = \text{VIL}$ .
  - \*3 Address valid prior to or coincident with  $\overline{CS1}$  transition low,  $\text{CS2}$  transition high.
  - \*4 Transition is specified at the point of  $\pm 500\text{mV}$  from steady state voltage with specified Load II in Fig. 2.



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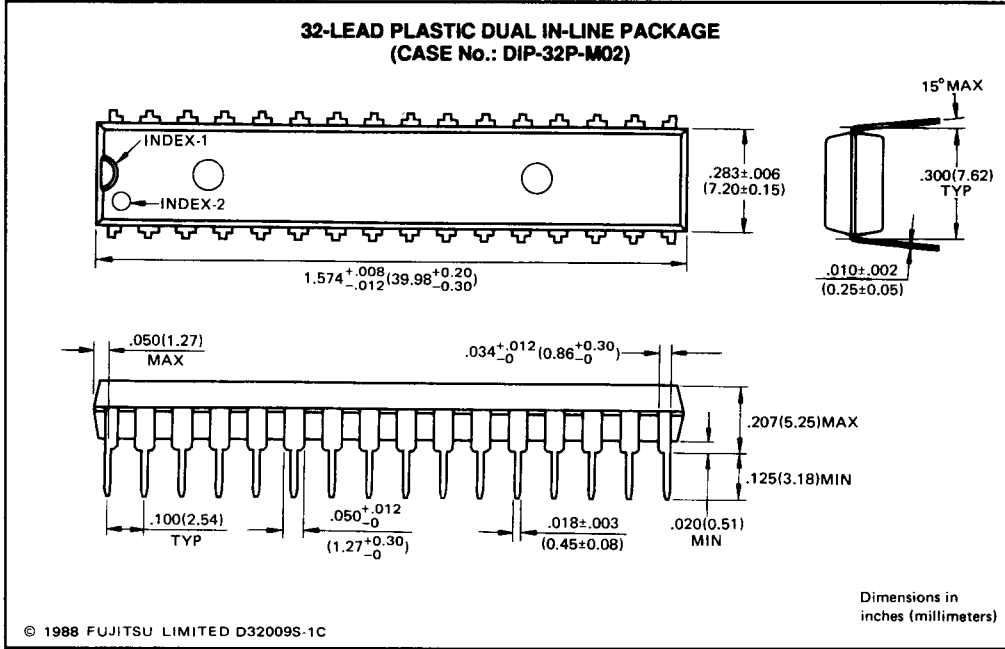
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- Note:**
- \*1 If  $\overline{CS}$  goes high simultaneously with  $\overline{WE}$  high, the output remains in high impedance state.
  - \*2 All Write Cycles are determined from the last address transition to the first address transition of next address.
  - \*3  $tWR$  is defined from the end point of Write Mode.
  - \*4 Transition is specified at the point of  $\pm 500mV$  from steady state voltage with specified Load II in Fig. 2.

# PACKAGE DIMENSIONS

PLASTIC DIP (Suffix: P-SK)



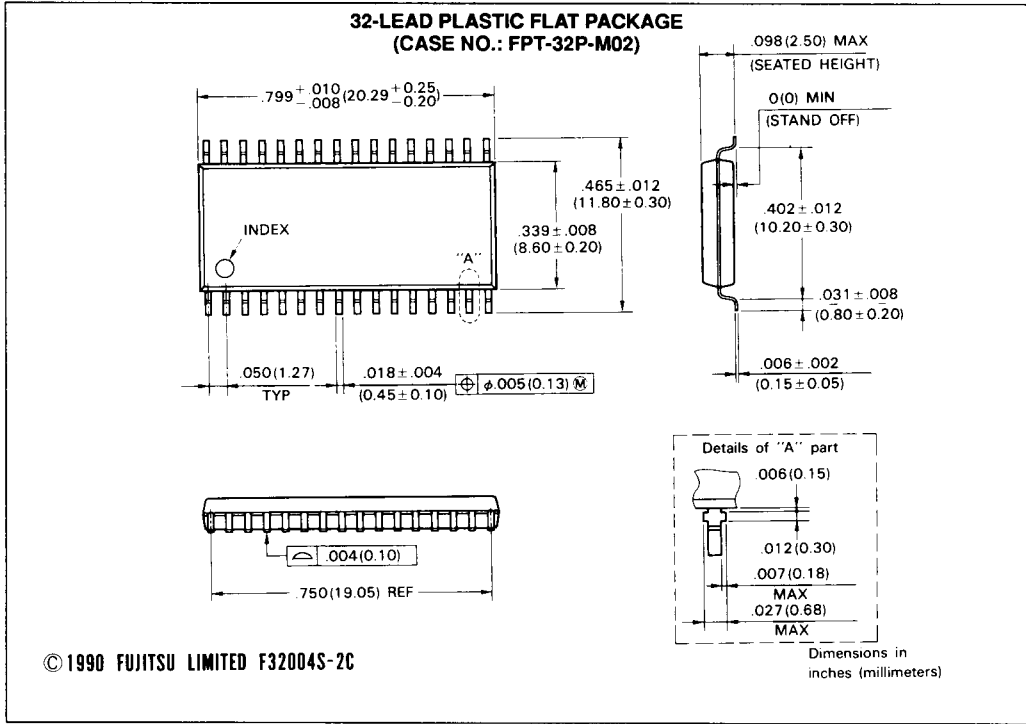
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**PACKAGE DIMENSIONS (Continued)**

Plastic FPT (Suffix: PF)

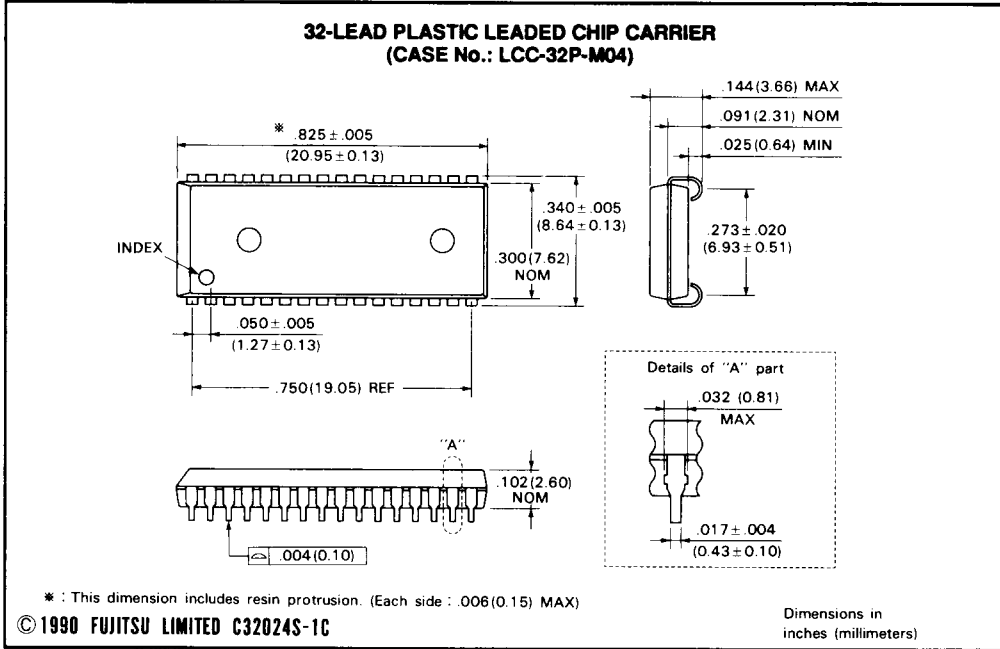
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# PACKAGE DIMENSIONS (Continued)

PLASTIC FPT (Suffix: PJ)



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